

## QUERY CONTROL FORM

**RTIS USE ONLY**

Application No. 09/629407  
Examiner-GAUJ Bruce - 2882

Prepared by SP  
Date 1/8/04  
No. of queries 1

Tracking Number 05875029  
Week Date 12/15/03  
IEU

## JACKET

- |                      |                        |                    |                |
|----------------------|------------------------|--------------------|----------------|
| a. Serial No.        | f. Foreign Priority    | k. Print Claim(s)  | p. PTO-1449    |
| b. Applicant(s)      | g. Disclaimer          | l. Print Fig.      | q. PTOL-85b    |
| c. Continuing Data   | h. Microfiche Appendix | m. Searched Column | r. Abstract    |
| d. PCT               | i. Title               | n. PTO-270/328     | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed      | o. PTO-892         | t. Other       |

## SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

## CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

**MESSAGE**

MESSAGE PTO 1449: Please, either initial or line through citations. Copy provided for reference.

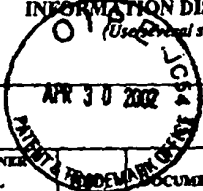
Thank you  
initials *KM*

## RESPONSE

initials

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<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>	Docket Number (Optional)	Application Number
	TWI-10820	09/629,407
	Applicant(s)	
	Allan Rosencwaig et al.	
	Filing Date	Group Art Unit
	August 1, 2000	2876



U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						Yes	No
CA	WO 01/71325	09/27/2001	PCT	G01N	23/00		

OTHER DOCUMENTS

*(Including Author, Title, Date, Pertinent Pages, Etc.)*

CB	E. Lüken et al., "Growth monitoring of W/Si X-ray multilayers by X-ray reflectivity and kinetic ellipsometry," SPIE, Vol. 2253, November 1994, pp. 327-332.					

Examiner	Date Considered
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include Copy of this form with next communication to applicant.	

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